

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Hiroyuki NAGASAKA et al.

Application No.: 10/581,307

Filed: September 26, 2006

Docket No.: 128253

For: EXPOSURE APPARATUS, EXPOSURE METHOD, METHOD FOR PRODUCING DEVICE, AND OPTICAL PART

INFORMATION DISCLOSURE STATEMENT

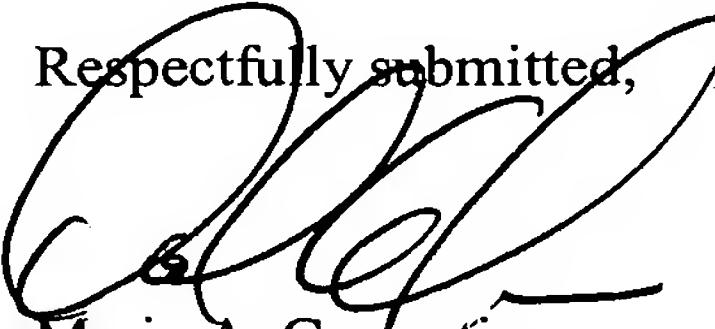
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- 2. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.
- 3. An English language Abstract of one or more non-English language reference is attached hereto. See References 118-130.

4. An English language translation of one or more Japanese Patent Publication cited herein has been obtained and is attached, but has not been reviewed for accuracy. See References 118-130.

Respectfully submitted,  
  
Mario A. Costantino  
Registration No. 33,565

Daniel A. Tanner, III  
Registration No. 54,734

MAC:DAT/emt

Date: September 29, 2006

**OLIFF & BERRIDGE, PLC**  
**P.O. Box 19928**  
**Alexandria, Virginia 22320**  
**Telephone: (703) 836-6400**

**DEPOSIT ACCOUNT USE  
AUTHORIZATION**  
Please grant any extension  
necessary for entry;  
Charge any fee due to our  
Deposit Account No. 15-0461

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 128253	APPLICATION NO. 10/581,307
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)		APPLICANTS Hiroyuki NAGASAKA et al.		
		FILING DATE September 26, 2006		

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name
	1	2005/0190455 A1	09/01/2005	ROSTALSKI et al.
	2	2005/0117224 A1	06/02/2005	SHAFER et al.
	3	2002/0163629 A1	11/07/2002	SWITKES et al.
	4	2003/0030916 A1	02/13/2003	SUENAGA
	5	2005/0141098 A1	06/30/2005	SCHUSTER
	6	2004/0000627 A1	01/01/2004	SCHUSTER
	7	2005/0030506 A1	02/10/2005	SCHUSTER
	8	2005/0217135 A1	10/06/2005	O'DONNELL et al.
	9	2005/0217137 A1	10/06/2005	SMITH et al.
	10	2005/0217703 A1	10/06/2005	O'DONNELL
	11	2004/0075895 A1	04/22/2004	LIN
	12	2004/0118184 A1	06/24/2004	VIOLETTE
	13	2004/0125351 A1	07/01/2004	KRAUTSCHIK
	14	2004/0180294 A1	09/16/2004	BABA-ALI et al.
	15	2004/0169924 A1	09/02/2004	FLAGELLO et al.
	16	2004/0227923 A1	11/18/2004	FLAGELLO et al.
	17	2003/0174408 A1	09/18/2003	ROSTALSKI et al.
	18	2004/0180299 A1	09/16/2004	ROLLAND et al.
	19	2004/0109237 A1	06/10/2004	EPPLE et al.

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation

## OTHER DOCUMENTS

Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	DATE CONSIDERED
----------	-----------------

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 128253	APPLICATION NO. 10/581,307
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)		APPLICANTS Hiroyuki NAGASAKA et al.		
		FILING DATE September 26, 2006		

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name
	20	2004/0257544 A1	12/23/2004	VOGEL et al.
	21	2004/0263808 A1	12/30/2004	SEWELL
	22	2005/0036183 A1	02/17/2005	YEO et al.
	23	2005/0036184 A1	02/17/2005	YEO et al.
	24	2005/0037269 A1	02/17/2005	LEVINSON
	25	2005/0036213 A1	02/17/2005	MANN et al.
	26	2004/0224265 A1	11/11/2004	ENDO et al.
	27	2004/0224525 A1	11/11/2004	ENDO et al.
	28	2005/0046934 A1	03/03/2005	HO et al.
	29	2005/0048223 A1	03/03/2005	PAWLOSKI et al.
	30	2004/0253547 A1	12/16/2004	ENDO et al.
	31	2004/0253548 A1	12/16/2004	ENDO et al.
	32	2005/0068639 A1	03/31/2005	PIERRAT et al.
	33	2005/0073670 A1	04/07/2005	CARROLL
	34	2005/0084794 A1	04/21/2005	MEAGLEY et al.
	35	2005/0094116 A1	05/05/2005	FLAGELLO et al.
	36	2005/0100745 A1	05/12/2005	LIN et al.
	37	2004/0136494 A1	07/15/2004	LOF et al.
	38	2004/0160582 A1	08/19/2004	LOF et al.

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation

## OTHER DOCUMENTS

Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	DATE CONSIDERED
Examiner:	Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 128253	APPLICATION NO. 10/581,307
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)		APPLICANTS Hiroyuki NAGASAKA et al.		
		FILING DATE September 26, 2006		

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name
	39	2004/0165159 A1	08/26/2004	LOF et al.
	40	2004/0207824 A1	10/21/2004	LOF et al.
	41	2004/0211920 A1	10/28/2004	MARIA DERKSON et al.
	42	2005/0036121 A1	02/17/2005	HOOGENDAM et al.
	43	2004/0169834 A1	09/02/2004	RICHTER et al.
	44	2004/0259040 A1	12/23/2004	ENDO et al.
	45	2004/0114117 A1	06/17/2004	BLEEKER
	46	2004/0259008 A1	12/23/2004	ENDO et al.
	47	2005/0110973 A1	05/26/2005	STREEFKERK et al.
	48	2005/0122497 A1	06/09/2005	LYONS et al.
	49	2004/0119954 A1	06/24/2004	KAWASHIMA et al.
	50	2005/0185269 A1	08/25/2005	EPPLE et al.
	51	2005/0225737 A1	10/13/2005	WEISSENRIEDER et al.
	52	2005/0132914 A1	06/23/2005	MULKENS et al.
	53	2005/0134815 A1	06/23/2005	VAN SANTEN et al.
	54	2005/0147920 A1	07/07/2005	LIN et al.
	55	2005/0145803 A1	07/07/2005	HAKEY et al.
	56	2005/0146694 A1	07/07/2005	TOKITA
	57	2005/0146695 A1	07/07/2005	KAWAKAMI

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation

## OTHER DOCUMENTS

Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	DATE CONSIDERED
----------	-----------------

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 128253	APPLICATION NO. 10/581,307
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)		APPLICANTS Hiroyuki NAGASAKA et al.		
		FILING DATE September 26, 2006		

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name
	58	2005/0153424 A1	07/14/2005	COON
	59	2005/0190435 A1	09/01/2005	SHAFER et al.
	60	2005/0158673 A1	07/21/2005	HAKEY et al.
	61	2005/0164502 A1	07/28/2005	DENG et al.
	62	2005/0270505 A1	12/08/2005	SMITH
	63	2005/0174549 A1	08/11/2005	DUINEVELD et al.
	64	2005/0175940 A1	08/11/2005	DIERICHS
	65	2005/0042554 A1	02/24/2005	DIERICHS et al.
	66	2005/0205108 A1	09/22/2005	CHANG et al.
	67	2005/0213061 A1	09/29/2005	HAKEY et al.
	68	2005/0213072 A1	09/29/2005	SCHENKER et al.
	69	2005/0219499 A1	10/06/2005	MARIA ZAAL et al.
	70	2005/0219482 A1	10/06/2005	BASELMANS et al.
	71	2005/0219481 A1	10/06/2005	COX et al.
	72	2005/0024609 A1	02/03/2005	DE SMIT et al.
	73	2005/0231694 A1	10/20/2005	KOLESNYCHENKO et al.
	74	2005/0237501 A1	10/27/2005	FURUKAWA et al.
	75	2005/0245005 A1	11/03/2005	BENSON
	76	2005/0243292 A1	11/03/2005	BASELMANS et al.
	77	2005/0253090 A1	11/17/2005	GAU et al.

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation

## OTHER DOCUMENTS

Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	DATE CONSIDERED
----------	-----------------

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 128253	APPLICATION NO. 10/581,307
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)		APPLICANTS Hiroyuki NAGASAKA et al.		
		FILING DATE September 26, 2006		

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name
	78	2005/0007569 A1	01/13/2005	STREEFKERK et al.
	79	2005/0259232 A1	11/24/2005	STREEFKERK et al.
	80	2004/0233405 A1	11/25/2004	KATO et al.
	81	2005/0259233 A1	11/24/2005	STREEFKERK et al.
	82	2005/0007570 A1	01/13/2005	STREEFKERK et al.
	83	2005/0264778 A1	12/01/2005	LOF et al.
	84	2005/0002004 A1	01/06/2005	KOLESNYCHENKO et al.
	85	2005/0030498 A1	02/10/2005	MULKENS
	86	2004/0263809 A1	12/30/2004	NAKANO
	87	2005/0018155 A1	01/27/2005	COX et al.
	88	2005/0018156 A1	01/27/2005	MULKENS et al.
	89	2005/0030497 A1	02/10/2005	NAKAMURA
	90	2005/0134817 A1	06/23/2005	NAKAMURA
	91	2005/0145265 A1	07/07/2005	RAVKIN et al.
	92	2005/0041225 A1	02/24/2005	SENGERS et al.
	93	2005/0046813 A1	03/03/2005	STREEFKERK et al.
	94	2005/0048220 A1	03/03/2005	MERTENS et al.
	95	2005/0030511 A1	02/10/2005	AUER-JONGEPIER et al.
	96	2005/0078286 A1	04/14/2005	DIERICHS et al.
	97	2005/0078287 A1	04/14/2005	SENGERS et al.

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation

## OTHER DOCUMENTS

Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	DATE CONSIDERED

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 128253	APPLICATION NO. 10/581,307
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)		APPLICANTS Hiroyuki NAGASAKA et al.		
		FILING DATE September 26, 2006		

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name
	98	2005/0233081 A1	10/20/2005	Tokita
	99	2005/0052632 A1	03/10/2005	Miyajima
	100	2005/0088635 A1	04/28/2005	Hoogendam et al.
	101	2005/0259236 A1	11/24/2005	Straaijer
	102	2005/0094114 A1	05/05/2005	Streefkerk et al.
	103	2005/0094119 A1	05/05/2005	Loopstra et al.
	104	2005/0074704 A1	04/07/2005	Endo et al.
	105	2005/0128445 A1	06/16/2005	Hoogendam et al.
	106	2005/0179877 A1	08/18/2005	Mulkens et al.
	107	2005/0174550 A1	08/11/2005	Streefkerk et al.
	108	2005/0263068 A1	12/01/2005	Hoogendam et al.
	109	2005/0106512 A1	05/19/2005	Endo et al.
	110	2005/0117135 A1	06/02/2005	Verhoeven et al.
	111	2005/0175776 A1	08/11/2005	Streefkerk et al.
	112	2005/0122505 A1	06/09/2005	Miyajima
	113	2005/0146693 A1	07/07/2005	Ohsaki
	114	2005/0136361 A1	06/23/2005	Endo et al.
	115	2005/0259234 A1	11/24/2005	Hirukawa et al.
	116	2006/0139614 A1	06/29/2006	Owa et al.
	117	6,940,582 B1	09/06/2005	Tanaka

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
	118	JP A 57-153433	09/22/1982	JAPAN	X	X
	119	JP A 58-202448	11/25/1983	JAPAN	X	X

## OTHER DOCUMENTS

Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	DATE CONSIDERED
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 128253	APPLICATION NO. 10/581,307
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)		APPLICANTS Hiroyuki NAGASAKA et al.		
		FILING DATE September 26, 2006		

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name	

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
	120	JP A 59-019912	02/01/1984	JAPAN	X	X
	121	JP A 62-065326	03/24/1987	JAPAN	X	X
	122	JP A 63-157419	06/30/1988	JAPAN	X	X
	123	JP A 04-305915	10/28/1992	JAPAN	X	X
	124	JP A 04-305917	10/28/1992	JAPAN	X	X
	125	JP A 05-062877	03/12/1993	JAPAN	X	X
	126	JP A 07-220990	08/18/1995	JAPAN	X	X
	127	JP A 10-303114	11/13/1998	JAPAN	X	X
	128	JP A 10-340846	12/22/1998	JAPAN	X	X
	129	JP A 11-176727	07/02/1999	JAPAN	X	X
	130	JP A 2000-058436	02/25/2000	JAPAN	X	X
	131	WO 2002/091078 A1	11/14/2002	WIPO		
	132	WO 2004/077154 A2	09/10/2004	WIPO		
	133	WO 2003/077037 A1	09/18/2003	WIPO		
	134	WO 2004/081666 A1	09/23/2004	WIPO		
	135	WO 2005/001432 A2	01/06/2005	WIPO		
	136	WO 2004/093159 A2	10/28/2004	WIPO		
	137	WO 2004/090634 A2	10/21/2004	WIPO		
	138	WO 2004/090633 A2	10/21/2004	WIPO		

## OTHER DOCUMENTS

Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	DATE CONSIDERED
----------	-----------------

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 128253	APPLICATION NO. 10/581,307
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)		APPLICANTS Hiroyuki NAGASAKA et al.		
		FILING DATE September 26, 2006		

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name		

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
	139	WO 2005/048328 A1	05/26/2005	WIPO		
	140	WO 2005/062351 A1	07/07/2005	WIPO		
	141	WO 2004/092833 A2	10/28/2004	WIPO		
	142	WO 2004/093160 A2	10/28/2004	WIPO		
	143	WO 2004/090577 A2	10/21/2004	WIPO		
	144	WO 2004/092830 A2	10/28/2004	WIPO		
	145	WO 2004/093130 A2	10/28/2004	WIPO		
	146	WO 2004/095135 A2	11/04/2004	WIPO		
	147	WO 2005/003864 A2	01/13/2005	WIPO		
	148	WO 2005/006026 A2	01/20/2005	WIPO		
	149	WO 2005/008339 A2	01/27/2005	WIPO		
	150	WO 2005/013008 A2	02/10/2005	WIPO		
	151	WO 2005/017625 A2	02/24/2005	WIPO		
	152	WO 2005/015283 A1	02/17/2005	WIPO		
	153	WO 2005/019935 A2	03/03/2005	WIPO		
	154	WO 2005/024325 A2	03/17/2005	WIPO		
	155	WO 2005/022266 A2	03/10/2005	WIPO		
	156	WO 2005/024517 A2	03/17/2005	WIPO		
	157	WO 2005/034174 A2	04/14/2005	WIPO		
	158	WO 2004/055803 A1	07/01/2004	WIPO		

## OTHER DOCUMENTS

Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	DATE CONSIDERED
Examiner:	Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 (REV. 1/06) <b>INFORMATION DISCLOSURE STATEMENT</b> (Use several sheets if necessary)			ATTY DOCKET NO. 128253		APPLICATION NO. 10/581,307
			APPLICANTS Hiroyuki NAGASAKA et al.		
			FILING DATE September 26, 2006		
<b>U.S. PATENT DOCUMENTS</b>					
Examiner Initials	Cite No.	Document Number	Date	Name	
<b>FOREIGN PATENT DOCUMENTS</b>					
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract With English Translation
	159	WO 2004/057589 A1	07/08/2004	WIPO	
	160	WO 2004/057590 A1	07/08/2004	WIPO	
	161	WO 2005/054953 A2	06/16/2005	WIPO	
	162	WO 2005/054955 A2	06/16/2005	WIPO	
	163	WO 2005/062128 A2	07/07/2005	WIPO	
	164	WO 2005/059617 A2	06/30/2005	WIPO	
	165	WO 2005/059654 A1	06/30/2005	WIPO	
	166	WO 2005/059645 A2	06/30/2005	WIPO	
	167	WO 2005/059618 A2	06/30/2005	WIPO	
	168	WO 2005/064405 A2	07/14/2005	WIPO	
	169	WO 2005/064400 A2	07/14/2005	WIPO	
	170	WO 2005/069055 A2	07/28/2005	WIPO	
	171	WO 2005/069081 A2	07/28/2005	WIPO	
	172	WO 2005/071491 A2	08/04/2005	WIPO	
	173	WO 2005/074606 A2	08/18/2005	WIPO	
	174	WO 2005/076084 A1	08/18/2005	WIPO	
	175	WO 2005/081067 A1	09/01/2005	WIPO	
	176	WO 2005/081030 A1	09/01/2005	WIPO	
	177	WO 2005/069078 A1	07/28/2005	WIPO	
	178	WO 2005/050324 A2	06/02/2005	WIPO	
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)			
EXAMINER				DATE CONSIDERED	
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 128253	APPLICATION NO. 10/581,307
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)		APPLICANTS Hiroyuki NAGASAKA et al.		
		FILING DATE September 26, 2006		

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name		

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
	179	WO 2005/098504 A1	10/20/2005	WIPO		
	180	WO 2005/098505 A1	10/20/2005	WIPO		
	181	WO 2005/098506 A1	10/20/2005	WIPO		
	182	WO 2005/106589 A1	11/10/2005	WIPO		
	183	WO 2005/111722 A2	11/24/2005	WIPO		
	184	WO 2005/111689 A2	11/24/2005	WIPO		
	185	WO 2005/119368 A2	12/15/2005	WIPO		
	186	WO 2005/119369 A1	12/15/2005	WIPO		
	187	WO 2005/001572 A2	01/06/2005	WIPO		

## OTHER DOCUMENTS

Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)
	189	Lin, B.J. "Semiconductor Foundry, Lithography, and Partners." Proceedings of SPIE, Vol. 4688, pp. 11 - 24, 2002.
	190	Switkes, M., et al. "Resolution Enhancement of 157nm Lithography by Liquid Immersion." Proceedings of SPIE, Vol. 4691, pp. 459 - 465, 2002.
	191	Switkes, M., et al. "Resolution Enhancement of 157nm Lithography by Liquid Immersion." J. Microlith., Microfab., Microsyst., Vol. 1, No. 3, pp. 1 - 4, 2002.
	192	Owa, Soichi, et al. "Nikon F2 Exposure Tool," slides 1 - 25, 3 <sup>rd</sup> 157nm Symposium, September 4, 2002.
	193	Owa, Soichi. "Immersion Lithography," slides 1 - 24, Immersion Lithography Workshop, December 11, 2002.
	194	Owa, Soichi, et al. "Immersion Lithography; its Potential Performance and Issues." Proceedings of SPIE, Vol. 5040, pp. 724 - 733, 2003.
	195	Owa, Soichi, et al. "Potential Performance and Feasibility of Immersion Lithography," slides 1 - 33, NGL Workshop 2003, July 2003.
	196	Owa, Soichi, et al. "Update on 193nm Immersion Exposure Tool," slides 1 - 38, Immersion Workshop 2004, January 27, 2004.
	197	Owa, Soichi, et al. "Update on 193nm Immersion Exposure Tool," slides 1 - 51, Litho Forum, January 28, 2004.

EXAMINER	DATE CONSIDERED
Examiner:	Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.